Abstract

An inspection apparatus inspects a shell structure in which a portion where a conductive part of a substrate and a contact part of a jig are electrically connected is sealed. The inspection apparatus comprises a housing, a probe configured to contact an electrode of the jig electrically connected to the contact part, a temperature adjustment medium circulation part configured to supply and discharge a temperature adjustment medium into and from the housing, and a control part. The control part controls (A) loading the shell structure into the housing and mounting the shell structure while the probe and the electrode are in contact with each other, (B) after (A), supplying the temperature adjustment medium into the housing and adjusting a temperature of the shell structure by immersing at least a part of the shell structure in the temperature adjustment medium, and (C) inspecting the substrate of the shell structure.